SAR_NOVAT_042_07002_MC950D_FCC





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This addendum supplements the SAR Test Report SAR NOVAT_042_07002_MC950D_FCC, section 8.

1. Test Settings

The device was tested with the following UE categories:

E-DCH Category 5

Maximum number of E_DCH codes transmitted = 2

Minimum spreading factor = SF2

TTI = 10ms only

Maximum number of bits of an E-DCH transport block transmitted = 20000

Data Rate = 2 Mbps

HS-DSCH Category 8

Maximum number of HS-DSCH codes received = 10

Minimum inter-TTI interval = 1

Maximum number of bits of an E-DCH transport block received = 14411

Total number of soft channel bits = 134400

Data Rate = 7.21 Mbps

Active Physical Channels:

DPCCH, DPDCH, HS-DPCCH, E-DPCCH, and E-DPDCH $_{\rm n}$ vary according to the sub-tests defined in the SAR Test Report.

Implementation of MPR form Qualcomm (the Chipset supplier of the EUT) is designed according to 3GPP TS 25.101 V6.14.0 (2006-12) Section 6.2.2 UE maximum output power with HS-DPCCH and E-DCH. Relevant power scaling is designed according to 3GPP TS 25.214 V6.11.0 (2006-12) Section 5.1.2.6 Maximum and minimum power limits.



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2. Sub-test Conducted Output Power

Sub-test parameters were setup using the CMU200 with engineering firmware installed. Some of the parameters that define the sub-tests could not be set directly. To insure proper configuration, procedures were followed from a supplemental operation manual, provided by Rhode & Schwarz. Refer to the CMU WCDMA Supplement V4x50.

FDDV		
Sub-test	Channel	dBm
1	4132	23.02
	4175	22.75
	4233	23.65
2	4132	23.53
	4175	22.08
	4233	22.11
3	4132	22.44
	4175	21.97
	4233	22.39
4	4132	21.87
	4175	23.57
	4233	22.61
5	4132	24.37
	4175	23.70
	4233	24.50

FDDII		
Sub-test	Channel	dBm
1	9262	22.18
	9400	21.87
	9538	22.41
2	9262	19.53
	9400	20.23
	9538	18.35
3	9262	19.86
	9400	20.58
	9538	19.10
4	9262	22.13
	9400	21.22
	9538	22.41
5	9262	22.72
	9400	22.70
	9538	22.72

The highlighted sub-tests represent the sub-test with the highest conducted power and the sub-test used for the SAR measurements.